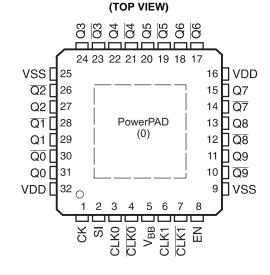
www.ti.com

# PROGRAMMABLE LOW-VOLTAGE 1:10 LVDS CLOCK DRIVER

Check for Samples: CDCLVD110A

#### **FEATURES**

- Low-Output Skew <30 ps (Typical) for Clock-Distribution Applications
- Distributes One Differential Clock Input to 10 LVDS Differential Clock Outputs
- V<sub>CC</sub> range 2.5 V ±5%
- Typical Signaling Rate Capability of Up to 1.1 GHz
- Configurable Register (SI/CK) Individually <u>Enables Disables Outputs</u>, Selectable CLK0, <u>CLK0</u> or CLK1, <u>CLK1</u> Inputs
- Full Rail-to-Rail Common-Mode Input Range
- Receiver Input Threshold ±100 mV
- Available in 32-Pin LQFP and QFN Package
- Fail-Safe I/O-Pins for V<sub>DD</sub> = 0 V (Power Down)



LQFP and QFN PACKAGE

### **APPLICATIONS**

 General purpose Industrial, Communication and Consumer Applications

### **DESCRIPTION**

The CDCLVD110A clock driver distributes one pair of differential LVDS clock inputs (either CLK0 or CLK1) to 10 pairs of differential clock outputs (Q0–Q9) with minimum skew for clock distribution. The CDCLVD110A is specifically designed to drive  $50-\Omega$  transmission lines.

When the control enable is high (EN = 1), the 10 differential outputs are programmable in that each output can be individually enabled/disabled (3-stated) according to the first 10 bits loaded into the shift register. Once the shift register is loaded, the last bit selects either CLK0 or CLK1 as the clock input. However, when EN = 0, the outputs are not programmable and all outputs are enabled.

The CDCLVD110A has an improved startup circuit that minimizes enabling time in AC- and DC-coupled systems.

The CDCLVD110A is characterized for operation from -40°C to 85°C.

ΔĀ

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PowerPAD is a trademark of Texas Instruments.

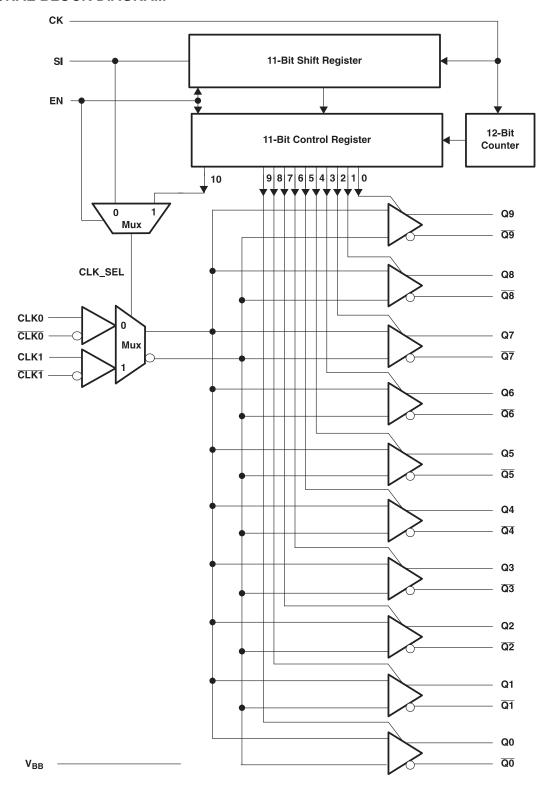




This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### **FUNCTIONAL BLOCK DIAGRAM**





#### **PIN FUNCTIONS**

	PIN	1/0	DECORPTION		
NAME	NO.	1/0	DESCRIPTION		
СК	1	ı	Control register input clock, features a 120-k. pullup resistor		
SI	2	I	Control register serial input/CLK Select, features a 120-k. pulldown resistor		
CLK0	3	I	True differential input, LVDS		
CLK0	4	I	Complementary differential input, LVDS		
$V_{BB}$	5	0	Reference voltage output		
CLK1	6	ı	True differential input, LVDS		
CLK1	7	I	Complementary differential input, LVDS		
EN	8	I	Control enable (for programmability), features a 120-k. pulldown resistor, input		
V <sub>SS</sub>	9, 25		Device ground		
$V_{DD}$	16, 32		Supply voltage		
Q [9:0]	11, 13, 15, 18, 20, 22, 24, 27, 29, 31	0	Clock outputs, these outputs provide low-skew copies of CLKIN		
Q[9:0]	10, 12, 14, 17, 19, 21,23, 26, 28, 30	0	Complementary clock outputs, these outputs provide low-skew copies of CLKIN		
PowerPAD™	0	I/O	The PowerPAD of the QFN32 package is thermally connected to the die to improve the heat transfer out of the package. This pad is connected to GND.		

### **ABSOLUTE MAXIMUM RATINGS**(1)

		VALUE	UNIT
$V_{DD}$	Supply voltage	-0.3 to 2.8	V
VI	Input voltage	-0.2 to (V <sub>DD</sub> + 0.2)	V
Vo	VI Output voltage	-0.2 to (V <sub>DD</sub> + 0.2)	V
I <sub>OSD</sub>	Driver short circuit current, Qn, Qn	Continuous	
ESD	Electrostatic discharge (HBM 1.5 kΩ, 100 pF)	>2000	V

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
$V_{DD}$	Supply voltage	2.375	2.5	2.625	V
$V_{IC}$	Receiver common-mode input voltage	0.5 V <sub>ID</sub>		$V_{DD}-0.5 \vert V_{ID} \vert$	V
$T_A$	Operating free-air temperature	-40		85	°C



### **ELECTRICAL CHARACTERISTICS**

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETI	ER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
DRIVE	र						
V <sub>OD</sub>	Differential outp	ut voltage	$R_L = 100\Omega$	250	450	600	mV
$\Delta V_{OD}$	V <sub>OD</sub> magnitude	change				50	mV
Vos	Offset voltage		-40°C to 85°C	0.95	1.2	1.45	V
ΔV <sub>OS</sub>	V <sub>OS</sub> magnitude	change				350	mV
	Outrout about air		V <sub>O</sub> = 0 V			-20	A
I <sub>OS</sub>	Output short circuit current		V <sub>OD</sub>   = 0 V			20	mA
$V_{BB}$	Reference outp	ut voltage	$V_{DD} = 2.5 \text{ V}, I_{BB} = -100 \mu\text{A}$	1.15	1.25	1.35	V
Co	Output capacita	nce	$V_O = V_{DD}$ or GND		3		pF
RECEIV	/ER						
$V_{IDH}$	Input threshold	high				100	mV
$V_{IDL}$	Input threshold	low		-100			mV
V <sub>ID</sub>	Input differentia	l voltage		200			mV
I <sub>IH</sub>	Input current, C	LK0/CLK0,	$V_{I} = V_{DD}$	-		_	
I <sub>IL</sub>	CLK1/CLK1		V <sub>I</sub> = 0 V	<del>-</del> 5		5	μA
C <sub>I</sub>	Input capacitan	ce	$V_{I} = V_{DD}$ or GND		3		pF
SUPPL	Y CURRENT						
		Full loaded	All outputs enabled and loaded, $R_L = 100 \Omega$ , $f = 100 MHz$		100	110	
$I_{DD}$	Cumply ours		All outputs enabled and loaded, $R_L = 100 \Omega$ , $f = 800 \text{ MHz}$		150	160	m 1
	Supply current	No load	Outputs enabled, no output load, f = 0 Hz			35	mA
I <sub>DDZ</sub>		3-State	All outputs 3-state by control logic, f = 0 Hz			35	

### **JITTER CHARACTERISTICS**

characterized with CDCLVD110 performance EVM,  $V_{DD}$  = 3.3 V, OUTPUTS NOT UNDER TEST are terminated to  $50\Omega$ 

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
4	Additive phase jitter from input to	12 kHz to 5 MHz, f <sub>out</sub> = 30.72 MHz		281		fo rmo
<sup>t</sup> jitterLVDS	LVDS output Q3 and Q3	12 kHz to 20 MHz, f <sub>out</sub> = 125 MHz		111		fs rms

Submit Documentation Feedback



### LVDS — SWITCHING CHARACTERISTICS

over recommended operating free-air temperature range,  $V_{DD}$  = 2.5 V ±5%

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay low-to-high	CLK0, <u>CLK0</u> CLK1, <u>CLK1</u>	Qn, Qn		2	3	ns
t <sub>PHL</sub>	Propagation delay high-to-low	CLK0, <u>CLK0</u> CLK1, <u>CLK1</u>	Qn, Qn		2	3	ns
t <sub>duty</sub>	Duty cycle	CLK0, <u>CLK0</u> CLK1, <u>CLK1</u>	Qn, Qn	45%		55%	
t <sub>sk(o)</sub>	Output skew		Any Qn, Qn		30		ps
t <sub>sk(p)</sub>	Pulse skew		Any Qn, Qn			50	ps
t <sub>sk(pp)</sub>	Part-to-part skew		Any Qn, Qn			600	ps
t <sub>r</sub>	Output rise time, 20% to 80%, $R_L$ = 100 $\Omega$ , $C_L$ = 5 pF		Any Qn, Qn			350	ps
t <sub>f</sub>	Output fall time, 20% to 80%, $R_L$ = 100 $\Omega$ , $C_L$ = 5 pF		Any Qn, Qn			350	ps
f <sub>clk</sub>	Max input frequency	CLK0, <u>CLK0</u> CLK1, <u>CLK1</u>	Any Qn, Qn	900	1100		MHz

### **CONTROL REGISTER CHARACTERISTICS**

over recommended operating free-air temperature range,  $V_{DD}$  = 2.5 V ±5% (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f <sub>MAX</sub>	Maximum frequency of shift register		100	150		MHz
t <sub>su</sub>	Setup time, clock to SI				2	ns
t <sub>h</sub>	Hold time, clock to SI				1.5	ns
t <sub>removal</sub>	Removal time, enable to clock				1.5	ns
t <sub>startup</sub>	Startup time after disable through SI				1.0	μs
t <sub>w</sub>	Clock pulse width, minimum		3			ns
$V_{IH}$	Logic input high	V <sub>DD</sub> = 2.5 V	2			V
$V_{IL}$	Logic input low	V <sub>DD</sub> = 2.5 V			8.0	V
	Input current, CK pin	$V_{l} = V_{DD}$	-5		5	
IH	Input current, SI and EN pins	$V_1 = V_{DD}$	10		-30	μA
	Input current, CK pin	V CND	-10		30	
IIL	Input current, SI and EN pins	V <sub>I</sub> = GND	-5		5	μΑ



### SPECIFICATION OF CONTROL REGISTER

The CDCLVD110A has an 11-bit, serial-in shift register and an 11-bit control register. The control Register enables/disables each output clock, and selects either CLK0 or CLK1 as the input clock. The CDCLVD110A has two modes of operation:

### Programmable Mode (EN=1)

The shift register uses a serial input (SI) and a clock input (CK). Once the shift register is loaded with 11 clock pulses, the 12th clock pulse loads the control register. The first bit (bit 0) on SI enables the Q9-Q9 output pair, and the 10th bit (bit 9) enables the Q0-Q0 pair. The 11th bit (bit 10) on SI selects either CLK0 or CLK1 as the input clock; a bit value of 0 selects CLK0, whereas a bit value of 1 selects CLK1. To restart the control register configuration, a reset of the state machine must be done with a clock pulse on CK (shift register clock input) and EN set to low. The control register can be configured only once after each reset.

### Standard Mode (EN=0)

In this mode, the CDCLVD110A is not programmable and all the clock outputs are enabled. The clock input (CLK0 or CLK1) is selected with the SI pin, as is shown in the table entitled control register.

STATE-MACHINE INPUTS									
EN	EN SI CK OUTPUT								
L	L	Х	All outputs enabled, CLK0 selected, control register disabled, default state						
L	Н	Х	All outputs enabled, CLK1 selected, control register disabled						
Н	L	1	First stage stores L, other stage stores data of previous stage						
Н	Н		First stage stores H, other stage stores data of previous stage						
L	Х		Reset of state machine, shift and control registers						

CONTROL REGISTER							
BIT 10	BITS [0-9]	Q <sub>N</sub> [0-9]					
L	Н	CLK0					
Н	Н	CLK1					
Х	L	Outputs disabled					

SERIAL INPUT (SI) SEQUENCE										
BIT 10	BIT 9	BIT 8	BIT 7	BIT 6	BIT 5	BIT 4	BIT 3	BIT 2	BIT 1	BIT 0
CLK_SEL	Q0	Q1	Q2	Q3	Q4	Q5	Q6	Q7	Q8	Q9

TRUTH TABL	E FOR CONTR	OL LOGIC						
CK	EN	SI	CLK0	CLK0	CLK1	CLK1	Q(0-9)	Q(0-9)
L	L	L	L	Н	Х	X	L	Н
L	L	L	Н	L	Х	X	Н	L
L	L	L	Open	Open	Х	X	L	Н
L	L	Н	X	Х	L	Н	L	Н
L	L	Н	X	Х	Н	L	Н	L
L	L	Н	X	Х	Open	Open	L	Н
All output	ts enabled				X = Don't care			

Submit Documentation Feedback



### **APPLICATION INFORMATION**

### **Fall-Safe Information**

For  $V_{DD}=0$  V (power-down mode) the CDCLVD110A has fail-safe input and output pins. In power-on mode, fail-safe biasing at input pins <u>can be acc</u>omplished with a 10-k $\Omega$  pullup resistor from CLK0/CLK1 to VDD and a 10-k $\Omega$  pulldown resistor from CLK0/CLK1 to GND.

### **LVDS Receiver Input Termination**

The LVDS receiver inputs require 100-Ω termination resistors placed as close as possible across the input pins.

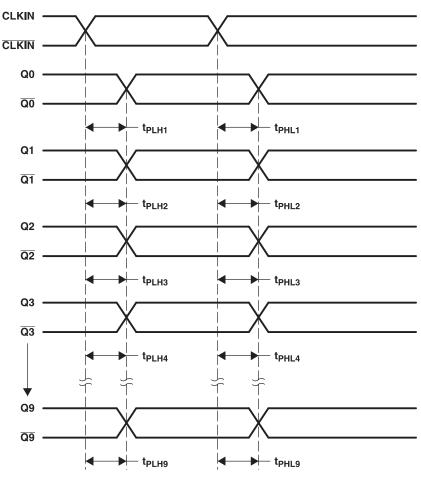
### **Control Inputs Termination**

No external termination is required. The CK control input has an internal 120-k $\Omega$  pullup resistor, while the SI– and EN–control inputs each have an internal 120-k $\Omega$  pulldown resistor. If the control pins are left open per the default, all outputs are enabled, CLK0, CLK0 is selected, and the control register is disabled.

Submit Documentation Feedback



### PARAMETER MEASUREMENT INFORMATION



- A. Output skew,  $t_{sk(0)}$ , is calculated as the greater of:
  - The difference between the fastest and the slowest  $t_{PLHn}$  (n = 1, 2,...10)
  - The difference between the fastest and the slowest  $t_{PHLn}$  (n = 1, 2,...10)
- B. Part-to-part skew,  $t_{sk(pp)}$ , is calculated as the greater of:
  - The difference between the fastest and the slowest  $t_{PLHn}$  (n = 1, 2,...10) across multiple devices
  - The difference between the fastest and the slowest  $t_{PHLn}$  (n = 1, 2,...10) across multiple devices
- C. Pulse skew,  $t_{sk(p)}$ , is calculated as the magnitude of the absolute time difference between the high-to-low  $(t_{PHL})$  and the low-to-high  $(t_{PLH})$  propagation delays when a single switching input causes one or more outputs to switch,  $t_{sk(p)} = |t_{PHL} t_{PLH}|$ . Pulse skew is sometimes referred to as pulse-width distortion or duty-cycle skew.

Figure 1. Waveforms for Calculation of  $t_{sk(p)}$  and  $t_{sk(pp)}$ 



### PARAMETER MEASUREMENT INFORMATION (continued)

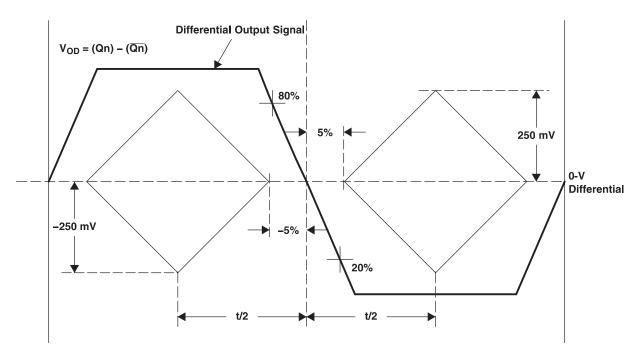


Figure 2. Test Criteria for  $f_{clk}$ , Duty Cycle,  $t_r$ ,  $t_f$ ,  $V_{OD}$ 

### **REVISION HISTORY**

C	hanges from Original (February 2007) to Revision A	Page
•	Changed Pinout Package title From: TQFP PACKAGE and QFN PACKAGE To: LQFP PACKAGE and QFN PACKAGE	
C	hanges from Revision A (January 2008) to Revision B	Page
• •	Changed Feature From: Available in 32-Pin LQFP Package To: Available in 32-Pin LQFP and QFN Package  Added Applications	
C	hanges from Revision B (October 2008) to Revision C	Page
•	Added PowerPAD information to the Pinout Package	





27-Jul-2013

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CDCLVD110ARHBR	ACTIVE	VQFN	RHB	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVD110A	Samples
CDCLVD110ARHBRG4	ACTIVE	VQFN	RHB	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVD110A	Samples
CDCLVD110ARHBT	ACTIVE	VQFN	RHB	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVD110A	Samples
CDCLVD110ARHBTG4	ACTIVE	VQFN	RHB	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVD110A	Samples
CDCLVD110AVF	ACTIVE	LQFP	VF	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKLVD110A	Samples
CDCLVD110AVFG4	ACTIVE	LQFP	VF	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKLVD110A	Samples
CDCLVD110AVFR	ACTIVE	LQFP	VF	32	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKLVD110A	Samples
CDCLVD110AVFRG4	ACTIVE	LQFP	VF	32	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	CKLVD110A	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



### **PACKAGE OPTION ADDENDUM**

27-Jul-2013

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 30-Jan-2014

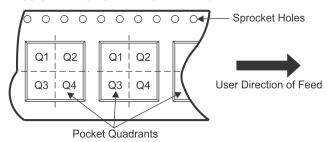
### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCLVD110ARHBR	VQFN	RHB	32	3000	330.0	12.4	5.3	5.3	1.5	8.0	12.0	Q2
CDCLVD110ARHBT	VQFN	RHB	32	250	180.0	12.4	5.3	5.3	1.5	8.0	12.0	Q2
CDCLVD110AVFR	LQFP	VF	32	1000	330.0	16.4	9.6	9.6	1.9	12.0	16.0	Q2

www.ti.com 30-Jan-2014

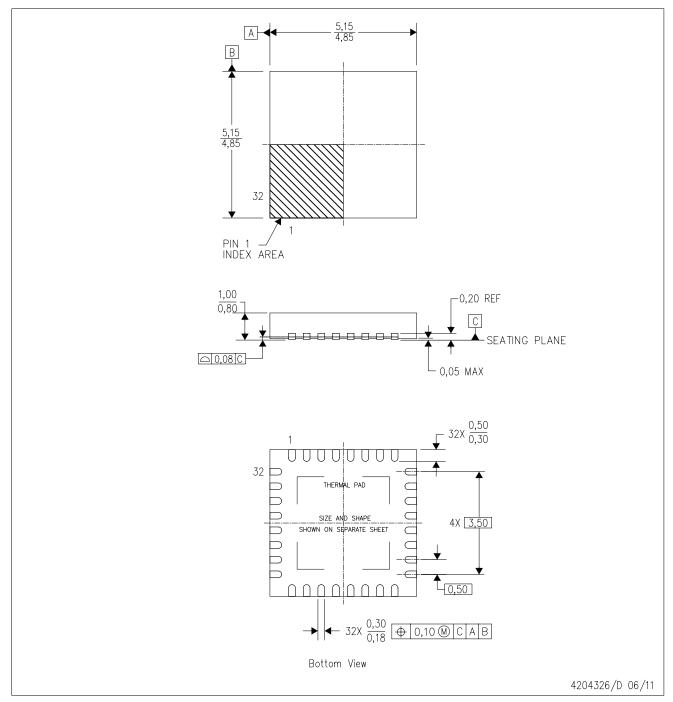


#### \*All dimensions are nominal

Device Package Type		Package Drawing	Pins SPQ		Length (mm)	Width (mm)	Height (mm)	
CDCLVD110ARHBR	VQFN	RHB	32	3000	338.1	338.1	20.6	
CDCLVD110ARHBT	VQFN	RHB	32	250	210.0	185.0	35.0	
CDCLVD110AVFR	LQFP	VF	32	1000	367.0	367.0	38.0	

# RHB (S-PVQFN-N32)

## PLASTIC QUAD FLATPACK NO-LEAD



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) Package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- F. Falls within JEDEC MO-220.



# RHB (S-PVQFN-N32)

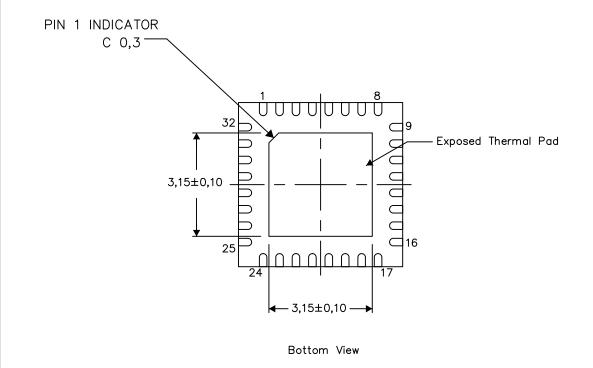
### PLASTIC QUAD FLATPACK NO-LEAD

### THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No—Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Exposed Thermal Pad Dimensions

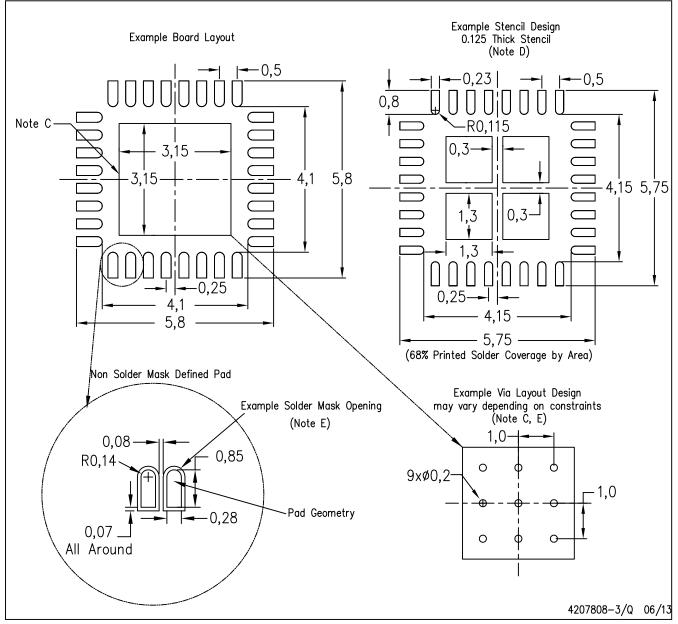
4206356-3/Y 06/13

NOTE: A. All linear dimensions are in millimeters



# RHB (S-PVQFN-N32)

# PLASTIC QUAD FLATPACK NO-LEAD



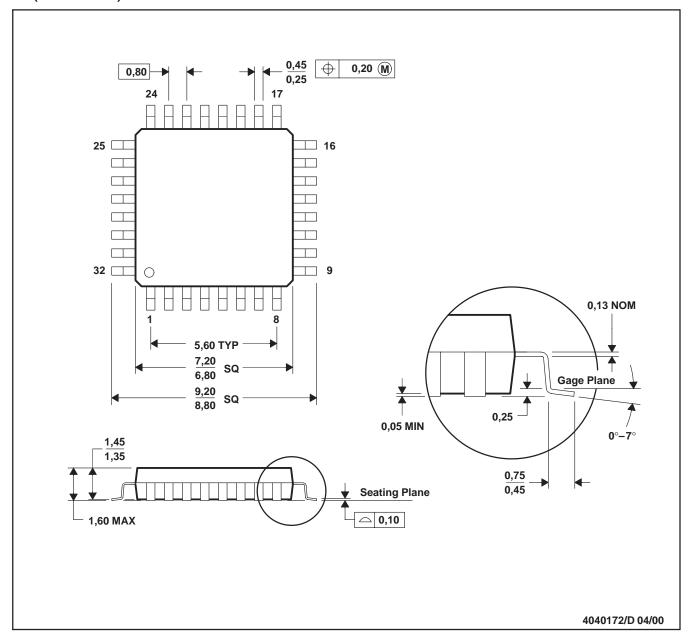
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <a href="http://www.ti.com">http://www.ti.com</a>.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- E. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.



# VF (S-PQFP-G32)

### PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

#### IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products Applications

Audio www.ti.com/audio Automotive and Transportation www.ti.com/automotive Communications and Telecom Amplifiers amplifier.ti.com www.ti.com/communications **Data Converters** dataconverter.ti.com Computers and Peripherals www.ti.com/computers **DLP® Products** www.dlp.com Consumer Electronics www.ti.com/consumer-apps

DSP **Energy and Lighting** dsp.ti.com www.ti.com/energy Clocks and Timers www.ti.com/clocks Industrial www.ti.com/industrial Interface interface.ti.com Medical www.ti.com/medical logic.ti.com Logic Security www.ti.com/security

Power Mgmt power.ti.com Space, Avionics and Defense www.ti.com/space-avionics-defense

Microcontrollers <u>microcontroller.ti.com</u> Video and Imaging <u>www.ti.com/video</u>

RFID <u>www.ti-rfid.com</u>

OMAP Applications Processors <u>www.ti.com/omap</u> TI E2E Community <u>e2e.ti.com</u>

Wireless Connectivity <u>www.ti.com/wirelessconnectivity</u>